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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/006,578	12/06/2001	Manoj K. Jain	T1-31858	4968	
23494	7590 02/19/2004		EXAM	EXAMINER	
TEXAS INSTRUMENTS INCORPORATED			LE, THAO X		
P O BOX 655 DALLAS, T	5474, M/S 3999 X 75265		ART UNIT	PAPER NUMBER	
21122110, 11			2814		
			DATE MAILED: 02/19/2004	4	

Please find below and/or attached an Office communication concerning this application or proceeding.

Application No.	Applicant(s)	8				
10/006,578	JAIN, MANOJ K.					
Examiner	Art Unit					
Thao X Le	2814					
pears on the cover sheet w	ith the correspondence address	••				
36(a). In no event, however, may a ly within the statutory minimum of thi will apply and will expire SIX (6) MOI e, cause the application to become A	reply be timely filed ty (30) days will be considered timely. NTHS from the mailing date of this communic BANDONED (35 U.S.C. § 133).	cation.				
December 2003.						
☑ This action is FINAL. 2b) ☐ This action is non-final.						
Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.						
e application. wn from consideration. or election requirement.						
er.						
10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.						
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ts have been received. ts have been received in a nity documents have beer u (PCT Rule 17.2(a)).	Application No n received in this National Stage	·				
Paper No. 5) Notice of	(s)/Mail Date Informal Patent Application (PTO-152)					
	Examiner Thao X Le pears on the cover sheet w Y IS SET TO EXPIRE 3 M 36(a). In no event, however, may a y within the statutory minimum of this will apply and will expire SIX (6) MOR a, cause the application to become Al g date of this communication, even if pecember 2003. In action is non-final. Ince except for formal mate Ex parte Quayle, 1935 C.D. In application. In election requirement. Per. Pepted or b) objected to drawing(s) be held in abeya ation is required if the drawing examiner. Note the attache of priority under 35 U.S.C. Its have been received. Its have been received in A with documents have been u (PCT Rule 17.2(a)). In of the certified copies not 4) Interview Paper Not Solution of the certified copies not 4) Interview Paper Not Solution of the certified copies not 4) Interview Paper Not Solution of the certified copies not 4) Interview Paper Not Solution of the certified copies not 4) Interview Paper Not Solution of the certified copies not 4) Interview Paper Not Solution of the certified copies not 4) Interview Paper Not Solution of the certified copies not 4) Interview Paper Not Solution of the certified copies not	10/006,578				

DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1, 4-9, 11-16 are rejected under 35 U.S.C. 103(a) as being unpatentable over US Patent 6291340 to Sandhu et al. in view of US 6436819 to Zhang et al.

Regarding to claims 1, 4, Sandhu discloses a method of forming a conductive structure in an integrated circuit in Fig. 1, comprising the steps of: forming a dielectric layer 32, column 6 line 57, over a semiconductor body, forming a hole 31, column 6 line 65, fig. 3, in dielectric layer 32, forming a conductive liner 35, column 7 line 1, in hole 31, annealing conductive liner, column 7 lines 16-22, forming a conductive barrier 41, column 7 line 13, fig. 4, filling hole 131 with a conductive material 62, column 7 line 30.

But, Sandhu does not expressly disclose after annealing conductive liner, treating conductive liner with plasma hydrogen.

However, Zhang reference discloses in fig. 8a-f a method wherein the conductive liner 806 is being treated with plasma 850 comprises hydrogen, column 11 lines 42-45. At the time the invention was made; it would have been obvious to one of ordinary skill in the art to combine the method of treating conductive liner with hydrogen of Zhang with Sandhu's method, because such hydrogen treatment would have improved the

metal/nitride stack film properties, including enhanced adhesion and barrier characteristics as taught by Zhang, see abstract.

Regarding to claims 5-7, 12-15, Sandhu does not disclose the hydrogen containing atmosphere comprises pure hydrogen or hydrogen mixed with a carrier gas.

But, Zhang reference discloses Zhang discloses different combinations of plasma gas, including N₂, H₂, NH₃, column 9 lines 57-59. It would have been obvious to one of ordinary skill in art to use teaching Zhang as claimed, because it would have produced the same results as discussed in the above claim 1. In addition, it has been held that where the general conditions of the claims are discloses in the prior art, it is not inventive to discover the optimum or workable range by routine experimentation. See In re Aller, 220 F.2d 454, 105 USPQ 233, 235 (CCPA 1955).

Regarding claims 8, 16, Sandhu does not discloses the method further comprising the step of repeating treating step prior to filling step.

But Zhang reference discloses the method further comprising the step of repeating treating step 852, fig. 8c, prior to filling step. At the time the invention was made; it would have been obvious to one of ordinary skill in the art to combine the method of treating conductive liner with hydrogen of Zhang with Sandhu's method, because such hydrogen treatment would have improved the metal/nitride stack film properties, including enhanced adhesion and barrier characteristics as taught by Zhang, see abstract.

Regarding to claims 9, 11, Sandhu discloses a method for forming a contact in an integrated circuit, comprising the steps of: forming a dielectric layer 32, column 6 line 57, over a semiconductor body, etching a contact hole 31, column 6 line 65, fig. 3, extending through

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dielectric layer 32, deposited titanium 35, column 7 line 1, in hole 31, over dielectric layer, including on exposed surface with contact hole, annealing titanium, column 7 lines 16-22, deposit TiN 41, column 7 line 13, fig. 4, over titanium, and then filling contact hole 131 with a tungsten 62, column 7 line 30.

But Sandhu does not expressly disclose the method comprising treating titanium with hydrogen prior to annealing step.

However, Zhang reference discloses the method comprising treating titanium with hydrogen. Zhang reference has demonstrated that the treating conductive liner with hydrogen at different stage of the process, fig. 5a-5e, 7a-7d, and 8a-8f has produced the same effects. At the time the invention was made; it would have been obvious to one of ordinary skill in the art to combine the method of treating conductive liner with hydrogen of Zhang with Sandhu's method prior to annealing titanium, because such hydrogen treatment would have improved the metal/nitride stack film properties, including enhanced adhesion and barrier characteristics as taught by Zhang, see abstract.

Response to Arguments

3. Applicant's arguments filed on 04/30/03 have been considered but are moot in view of the new ground(s) of rejection.

Conclusion

4. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, THIS ACTION IS MADE FINAL. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Thao X Le whose telephone number is (571) 272-1708. The examiner can normally be reached on M-F from 8:00 AM - 4:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael M Fahmy can be reached on (571) 272 -1705. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Thao X. Le 10 Feb. 2004

ONG PHAM